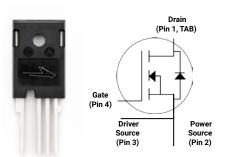


Silicon Carbide Power MOSFET C3M™ MOSFET Technology

N-Channel Enhancement Mode

Features

- C3M[™] SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant







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Ordering Part Number	Package	Marking	
C3M0120065K	TO-247-4	C3M0120065K	

Applications

- Solar inverters
- DC/DC converters
- Switch Mode Power Supplies
- EV battery chargers
- UPS

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

Key Parameters

Parameter	Symbol	Min.	Тур.	Max	Unit	Conditions	Note
Drain - Source Voltage	V _{DS}			650		T _c = 25°C	
Maximum Gate - Source Voltage	V _{GS(max)}	-8		+19	v	Transient	
Operational Gate-Source Voltage	V _{GS op}		-4/15			Static	Note 1
DC Continuous Drain Current	I _D			22		$V_{GS} = 15 \text{ V}, T_{C} = 25 \text{ °C}, T_{J} \le 175 \text{ °C}$	Fig. 19 Note 2
				16	A	$V_{GS} = 15 \text{ V}, T_{C} = 100 \text{ °C}, T_{J} \le 175 \text{ °C}$	
Pulsed Drain Current	I _{DM}			51		t_{pmax} limited by T_{jmax} $V_{GS} = 15V$, $T_{C} = 25$ °C	Fig. 22
Power Dissipation	P _D			98	w	$T_c = 25^{\circ} C, T_J = 175^{\circ} C$	Fig. 20
Operating Junction and Storage Temperature	T_{J},T_{stg}			-40 to +175	°C		
Solder Temperature	T _L			260		According to JEDEC J-STD-020	
Mounting Torque	M _D			1 8.8	Nm Ibf-in	M3 or 6-32 screw	

Note (1): Recommended turn-on gate voltage is 15V with ±5% regulation tolerance, see Application Note PRD-04814 for additional details Note (2): Verified by design

Electrical Characteristics ($T_c = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Note	
Drain-Source Breakdown Voltage	V _{(BR)DSS}	650	_	_		$V_{DS} = 0 \text{ V}, I_{D} = 100 \mu\text{A}$		
	.,	1.8	2.3	3.6	V	V _{DS} = V _{GS} , I _D = 1.86 mA	F: 44	
Gate Threshold Voltage	V _{GS(th)}	_	1.9	_		$V_{DS} = V_{GS}, I_D = 1.86 \text{ mA}, T_J = 175^{\circ}\text{C}$	Fig. 11	
Zero Gate Voltage Drain Current	I _{DSS}	_	1	50	μΑ	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$		
Gate-Source Leakage Current	I _{GSS}	_	10	250	nA	$V_{GS} = 15 \text{ V}, V_{DS} = 0 \text{ V}$		
Drain-Source On-State Resistance	D	_	120	157	mΩ	$V_{GS} = 15 \text{ V}, I_D = 6.76$	Fig.	
	R _{DS(on)}	_	168	_	11122	$V_{GS} = 15 \text{ V}, I_D = 6.76, T_J = 175^{\circ}\text{C}$	4, 5, 6	
Transconductance	σ.		5.0		S	$V_{DS} = 20 \text{ V}, I_{DS} = 6.76 \text{ A}$	Fig. 7	
Transconductance	g fs		4.9		3	$V_{DS} = 20 \text{ V}, I_{DS} = 6.76 \text{ A}, T_{J} = 175^{\circ}\text{C}$	11g. 1	
Input Capacitance	C _{iss}	_	640	_		$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V to } 400 \text{ V}$	Fig. 17, 18	
Output Capacitance	C _{oss}	_	45	_		f = 1 Mhz		
Reverse Transfer Capacitance	C _{rss}	_	2.3	_	pF	V _{AC} = 25 mV		
Effective Output Capacitance (Energy Related)	C _{o(er)}	_	57	_		V = 0 V V = 0 V + 0 400 V		
Effective Output Capacitance (Time Related)	C _{o(tr)}	_	79	_		$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V to } 400 \text{ V}$	Note 3	
C _{oss} Stored Energy	E _{oss}	_	4.3	_		$V_{DS} = 400 \text{ V}, f = 1 \text{ Mhz}$	Fig. 16	
Turn-On Switching Energy (Body Diode)	E _{on}	_	34	_		$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_D = 6.76 \text{ A},$ $R_{G(ext)} = 10 \Omega, L = 237 \mu\text{H}, T_J = 175^{\circ}\text{C}$	F:- 2F	
Turn Off Switching Energy (Body Diode)	E _{off}	_	7	_	μJ	FWD = Internal Body Diode of MOSFET		
Turn-On Switching Energy (External Diode)	E _{on}	_	27	_	$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_{D} = 6.76 \text{ A},$		Fig. 25	
Turn Off Switching Energy (External Diode)	E _{off}	-	7	_		$R_{G(ext)} = 10 \Omega$, L= 237 μ H, $T_J = 175$ °C FWD = External SiC DIODE		
Turn-On Delay Time	t _{d(on)}	_	8	_				
Rise Time	t _r	_	11	_		$V_{DD} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$ $I_D = 6.76 \text{ A}, R_{G(ext)} = 10 \Omega$	Fig. 26	
Turn-Off Delay Time	$t_{d(off)}$	_	19	_	ns	Timing relative to V _{DS} Inductive load		
Fall Time	t _f	_	11	_		inductive toad		
Internal Gate Resistance	R _{G(int)}	_	6	_	Ω	f = 1 MHz, V _{AC} = 25 mV		
Gate to Source Charge	$Q_{\rm gs}$	_	8	_		V -400 V V - 4 V/15 V		
Gate to Drain Charge	Q_{gd}	_	10	_	nC	$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$ $I_{D} = 6.76 \text{ A}$	Fig. 12	
Total Gate Charge	Qg	_	28	_		Per IEC60747-8-4 pg 21		

Note

 $^{^3}$ C_{o(et)}, a lumped capacitance that gives same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V C_{o(tr)}, a lumped capacitance that gives same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Reverse Diode Characteristics ($T_c = 25$ °C unless otherwise specified)

Parameter	Symbol	Тур.	Max.	Unit	Test Conditions	Notes
Diada Famuard Valtage	V	4.5	_	V	$V_{GS} = -4 \text{ V}, I_{SD} = 3.4 \text{ A}, T_{J} = 25^{\circ}\text{C}$	Fig. 8, 9, 10
Diode Forward Voltage	V_{SD}	4.0	_		V _{GS} = -4 V, I _{SD} = 3.4 A, T _J = 175°C	
Continuous Diode Forward Current	Is	_	16		V _{GS} = -4 V, T _C = 25°C	
Diode pulse Current	I _{S, pulse}	_	51	A	V _{GS} = -4 V, pulse width t _P limited by T _{jmax}	
Reverse Recover Time	t _{rr}	8	_		V _{GS} = -4 V, I _{SD} = 6.76 A, V _R = 400 V dif/dt = 6245 A/μs, T ₁ = 175°C	
Reverse Recovery Charge	Qrr	119	_	ns		
Peak Reverse Recovery Current	I _{RRM}	22	_	6	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	
Reverse Recover Time	t _{rr}	15	_	nC		
Reverse Recovery Charge	Qrr	89	_		$V_{GS} = -4 \text{ V}, I_{SD} = 6.76 \text{ A}, V_{R} = 400 \text{ V}$ dif/dt = 1845 A/µs, T ₁ = 175°C	
Peak Reverse Recovery Current	I _{RRM}	10	_	A	Σ, 2 2, μο, τη 2 ο	

Thermal Characteristics

Parameter	Symbol	Тур.	Unit	Note
Thermal Resistance from Junction to Case	R _{θJC}	1.53	96.04	Fig. 21
Thermal Resistance From Junction to Ambient	$R_{\theta JA}$	40	°C/W	

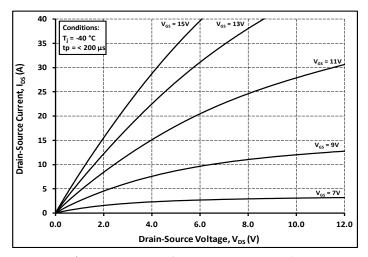


Figure 1. Output Characteristics T_J = -40°C

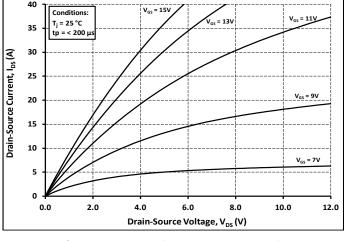


Figure 2. Output Characteristics T_J = 25°C

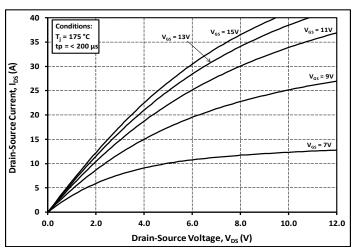


Figure 3. Output Characteristics T_J = 175°C

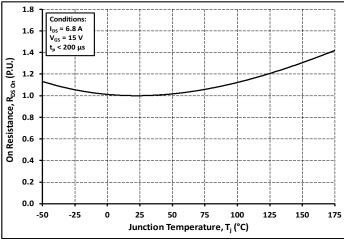


Figure 4. Normalized On-Resistance vs. Temperature

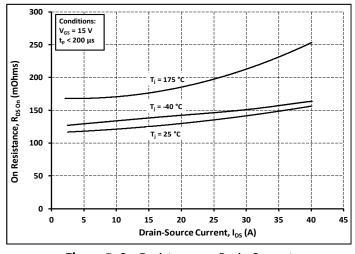


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

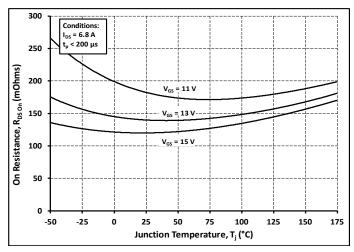


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

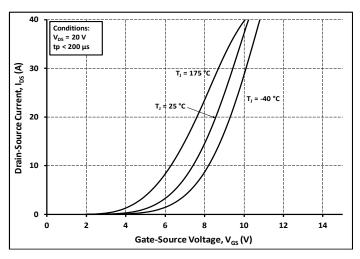


Figure 7. Transfer Characteristic for Various Junction Temperatures

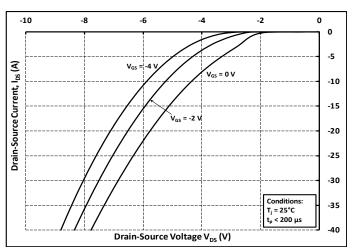


Figure 9. Body Diode Characteristic at 25°C

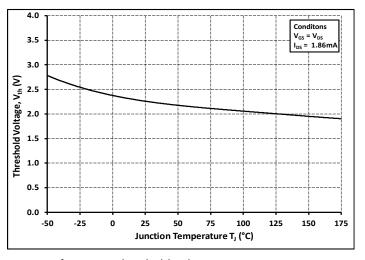


Figure 11. Threshold Voltage vs. Temperature

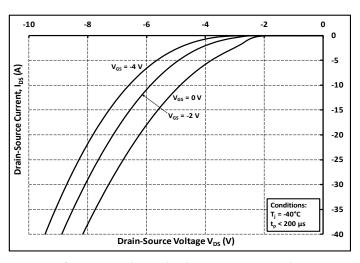


Figure 8. Body Diode Characteristic at -40°C

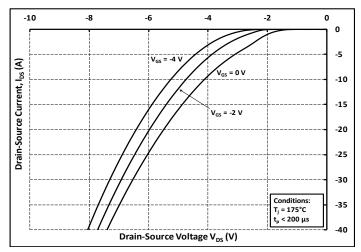


Figure 10. Body Diode Characteristic at 175°C

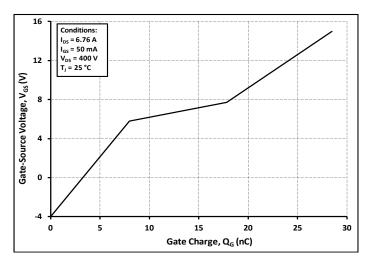


Figure 12. Gate Charge Characteristics

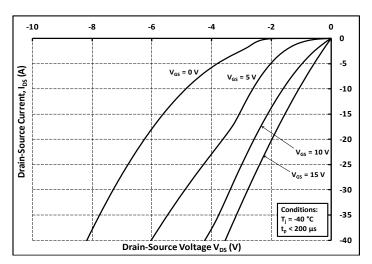
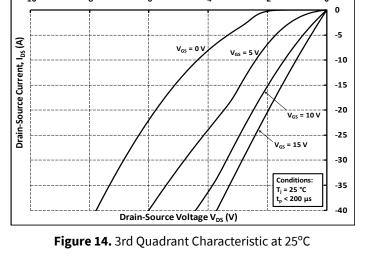


Figure 13. 3rd Quadrant Characteristic at -40°C



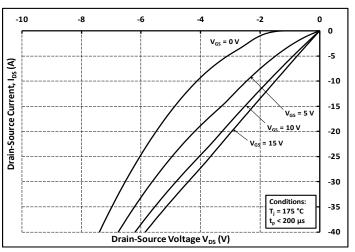


Figure 15. 3rd Quadrant Characteristic at 175°C

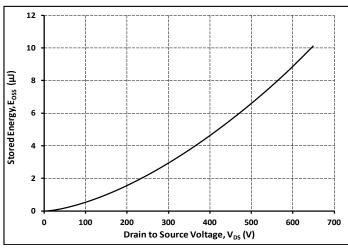


Figure 16. Output Capacitor Stored Energy

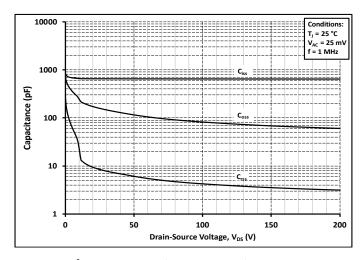


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

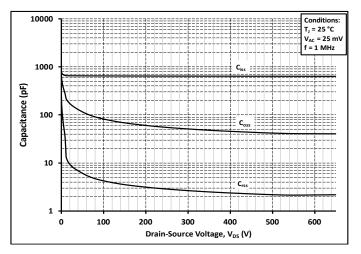


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)

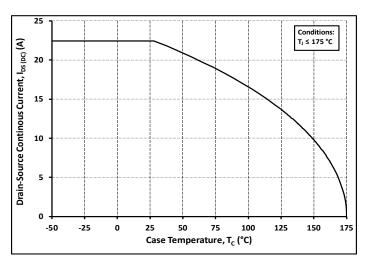


Figure 19. Continuous Drain Current Derating vs. Case Temperature

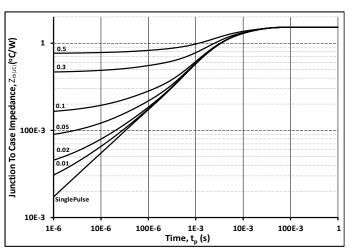


Figure 21. Transient Thermal Impedance (Junction - Case)

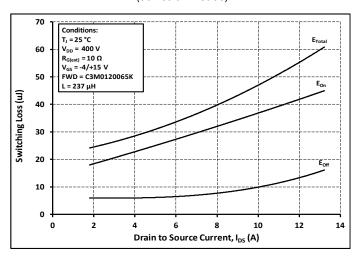


Figure 23. Clamped Inductive Switching Energy vs. Drain Current $(V_{DD} = 400V)$

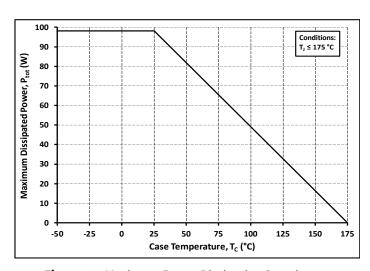


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

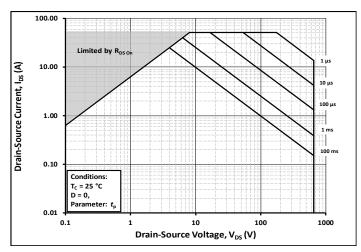


Figure 22. Safe Operating Area

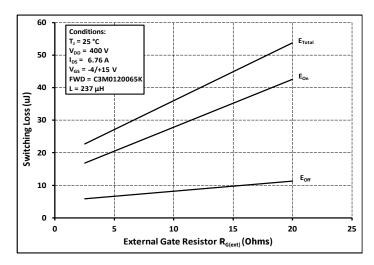


Figure 24. Clamped Inductive Switching Energy vs. R_{G(ext)}

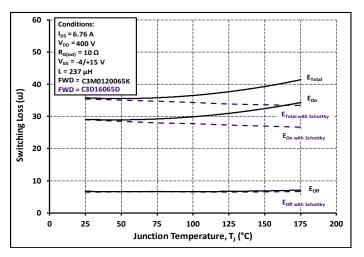


Figure 25. Clamped Inductive Switching Energy vs. Temperature

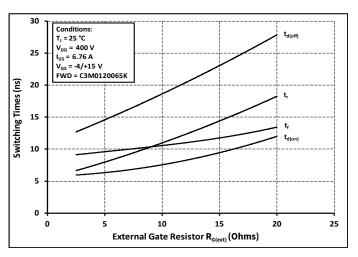


Figure 26. Switching Times vs. R_{G(ext)}

Test Circuit Schematic

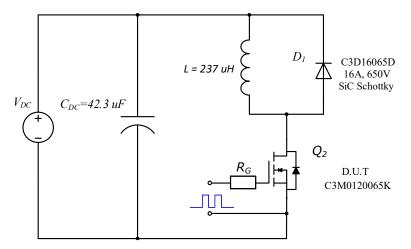


Figure 27. Clamped Inductive Switching Waveform Test Circuit

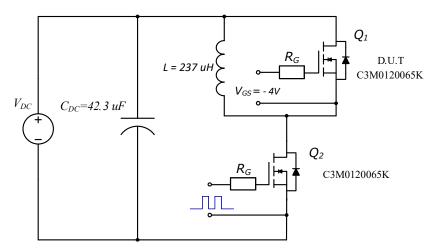
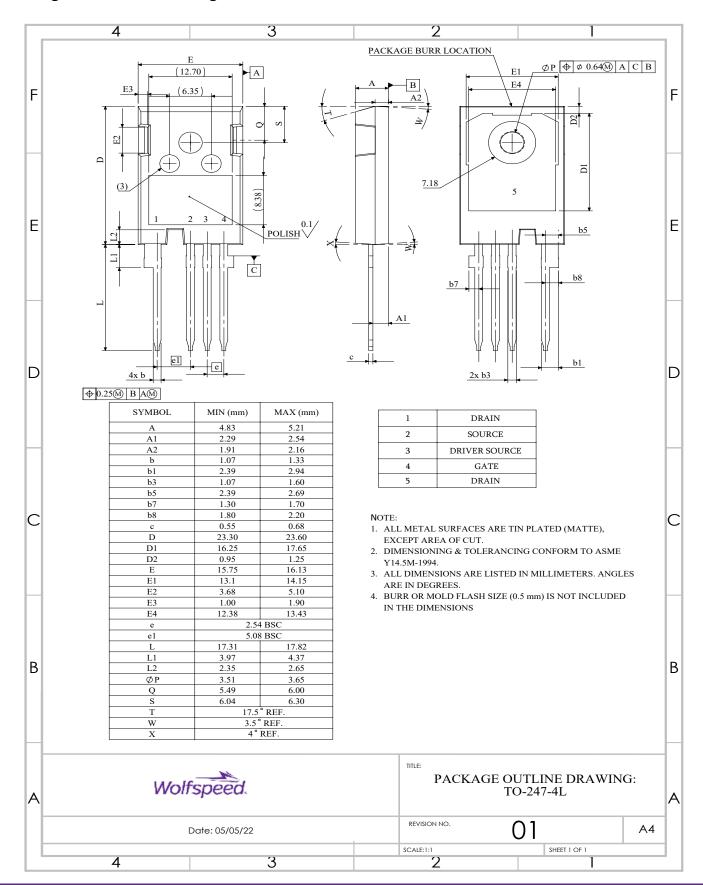


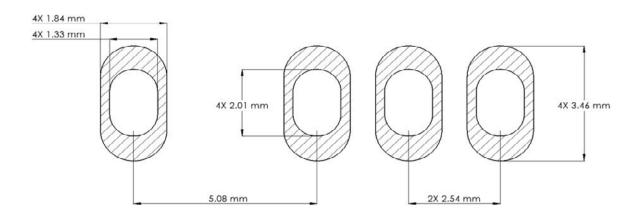
Figure 28. Body Diode Recovery Test Circuit

Package Dimensions - Package TO-247-4L





Recommended Solder Pad Layout



Revision History

Current Revision	Date of Release	Description of Changes
1	January-2021	N/A
2	December-2023	Updated Wolfspeed branding, package drawing, package image, and solder pad layout, added Revision History Table, Table 1 layout revised

Related Links

- SPICE Models
- SiC MOSFET Isolated Gate Driver reference design
- SiC MOSFET Evaluation Board

Notes & Disclaimer

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The Silicon Carbide MOSFET module switches at speeds beyond what is customarily associated with IGBT-based modules. Therefore, special precautions are required to realize optimal performance. The interconnection between the gate driver and module housing needs to be as short as possible. This will afford optimal switching time and avoid the potential for device oscillation. Also, great care is required to insure minimum inductance between the module and DC link capacitors to avoid excessive VDS overshoot.

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Wolfspeed representative or from the Product Documentation sections of www.wolfspeed.com.

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REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact your Wolfspeed representative to ensure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

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